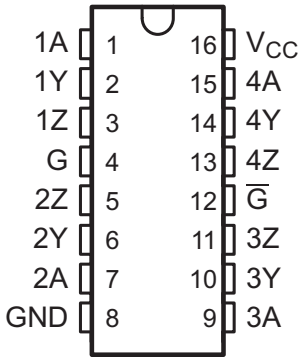
高速差分线路驱动器

查询样品: SN55LVDS31-SP

特性

- 符合 **QML-V，SMD 5962-97621**
- 符合或者超过 **ANSI TIA/EIA-644** 标准的要求
- 具有 **350mV** 的典型输出电压和 **100Ω** 负载的低压差分信号传输
- 典型输出电压上升和下降次数为 **500ps**（**400Mbps** 时）
- 典型传播延迟时间为 **1.7ns**
- 由一个单 **3.3V** 电源供电运行
- 每个驱动器在 **200MHz** 上的功率耗散典型值为 **25mW**
- 当被禁用或者 V_{CC} **= 0** 时，驱动器处于高阻抗
- 总线-端子静电放电 **(ESD)** 保护超过 **8kV**
- 低压 **TTL(LVTTL)** 逻辑输入电平
- 针对有冗余需求的太空和高可靠性应用的冷备用

J OR W PACKAGE
(TOP VIEW)



说明

SN55LVDS31 是一款差分线路驱动器，此驱动器能够执行低压差分信号传输 (LVDS) 的电气特性。 这个信号传输技术降低了 5V 差分标准电平（例如 TIA/EIA-422B）的输出电压电平，从而减少了功耗、增加了开关速度、并可实现 3.3V 电源轨供电下的运行。 当被启用时，这个驱动器将传送一个大小为 247mV 的最小差分输出电压进入 100Ω 的负载。

此器件和信号传输技术用于接近 100Ω 的受控阻抗介质上的点到点和多支路（一个驱动器和多个接收器）的数据传输应用。此传输介质可以是印刷电路板走线、底板、或者电缆。 数据传输的最终速率和距离取决于介质的衰减特性和环境的噪声耦合。

SN55LVDS31 额定运行温度介于 -55°C 至 125°C 之间。

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of the Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

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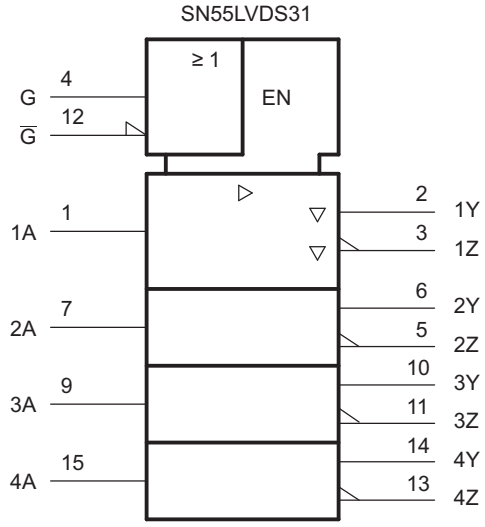
These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

ORDERING INFORMATION(1)

T_A	PACKAGE(2)	ORDERABLE PART NUMBER	TOP-SIDE MARKING
–55°C to 125°C	CDIP - J	5962-9762101VEA	5962-9762101VEA
	CFP - W	5962-9762101VFA	5962-9762101VFA

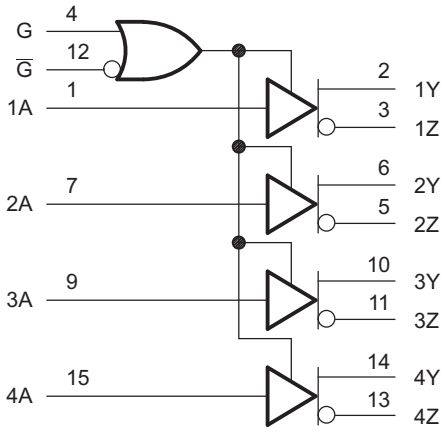
(1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.
(2) Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

Logic Symbol



This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

SN55LVDS31 Logic Diagram (Positive Logic)



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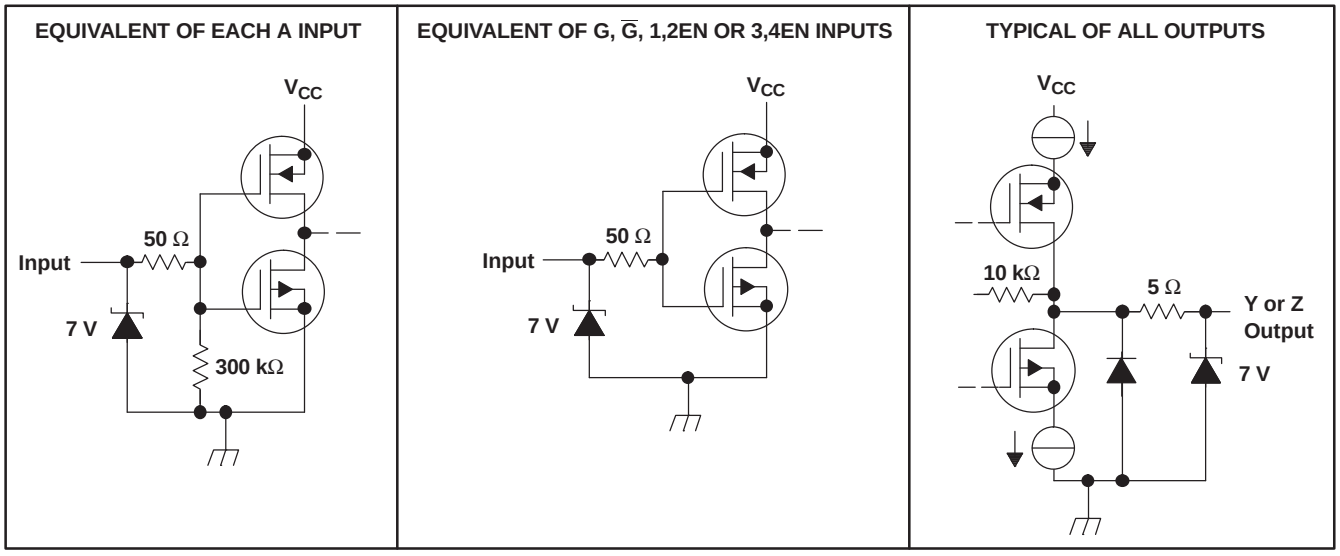
FUNCTION TABLE

Table 1. SN55LVDS31 (1)

INPUT A	ENABLES		OUTPUTS	
	G	G	Y	Z
H	H	X	H	L
L	H	X	L	H
H	X	L	H	L
L	X	L	L	H
X	L	H	Z	Z
Open	H	X	L	H
Open	X	L	L	H

(1) H = high level, L = low level, X = irrelevant, Z = high impedance (off)

EQUIVALENT INPUT AND OUTPUT SCHEMATIC DIAGRAMS



ABSOLUTE MAXIMUM RATINGS(1)

over operating free-air temperature range (unless otherwise noted)

		UNIT
V_{CC}	Supply voltage range(2)	–0.5 V to 4 V
V_I	Input voltage range	–0.5 V to V_{CC} + 0.5 V
	Continuous total power dissipation	See Dissipation Rating Table
	Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C
T_{stg}	Storage temperature range	–65°C to 150°C

(1) Stresses beyond those listed under *absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *recommended operating conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
(2) All voltages, except differential I/O bus voltages, are with respect to the network ground terminal.

DISSIPATION RATING TABLE

PACKAGE	$T_A \le 25°C$ POWER RATING	DERATING FACTOR(1) ABOVE $T_A = 25°C$	$T_A = 70°C$ POWER RATING	$T_A = 85°C$ POWER RATING	$T_A = 125°C$ POWER RATING
J	1375 mW	11 mW/°C	880 mW	715 mW	275 mW
W	1000 mW	8 mW/°C	640 mW	520 mW	200 mW

(1) This is the inverse of the junction-to-ambient thermal resistance when board-mounted and with no air flow.

RECOMMENDED OPERATING CONDITIONS

		MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage	3	3.3	3.6	V
V_{IH}	High-level input voltage	2			V
V_{IL}	Low-level input voltage			0.8	V
T_A	Operating free-air temperature	–55		125	°C

ELECTRICAL CHARACTERISTICS

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP(1)	MAX	UNIT
V_{OD}	Differential output voltage magnitude	R_L = 100 Ω,	See Figure 2	247	340	454	mV
ΔV_{OD}	Change in differential output voltage magnitude between logic states	R_L = 100 Ω,	See Figure 2	–50		50	mV
$V_{OC(SS)}$	Steady-state common-mode output voltage	See Figure 3		1.125	1.2	1.375	V
$\Delta V_{OC(SS)}$	Change in steady-state common-mode output voltage between logic states	See Figure 3		–50		50	mV
$V_{OC(PP)}$	Peak-to-peak common-mode output voltage	See Figure 3			50		mV
I_{CC}	Supply current	V_I = 0.8 V or 2 V,	Enabled, No load		9	20	mA
		V_I = 0.8 or 2 V,	R_L = 100 Ω, Enabled		25	35	
		V_I = 0 or V_{CC},	Disabled		0.25	1	
I_{IH}	High-level input current	V_{IH} = 2			4	20	µA
I_{IL}	Low-level input current	V_{IL} = 0.8 V			0.1	10	µA
I_{OS}	Short-circuit output current	$V_{O(Y)}$ or $V_{O(Z)}$ = 0			–4	–24	mA
		V_{OD} = 0				±12	
I_{OZ}	High-impedance output current	V_O = 0 or 2.4 V				±1	µA
$I_{O(OFF)}$	Power-off output current	V_{CC} = 0,	V_O = 2.4 V			±4	µA
C_i	Input capacitance				3		pF

(1) All typical values are at T_A = 25°C and with V_{CC} = 3.3 V.

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SWITCHING CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP(1)	MAX	UNIT
t_{PLH}	Propagation delay time, low-to-high-level output	R_L = 100 Ω, C_L = 10 pF, See Figure 2	0.5	1.4	4	ns
t_{PHL}	Propagation delay time, high-to-low-level output		1	1.7	4.5	ns
t_r	Differential output signal rise time (20% to 80%)		0.4	0.5	1	ns
t_f	Differential output signal fall time (80% to 20%)		0.4	0.5	1	ns
$t_{sk(p)}$	Pulse skew ($\|t_{PHL} - t_{PLH}\|$)			0.3	0.6	ns
$t_{sk(o)}$	Channel-to-channel output skew(2)			0.3	0.6	ns
t_{PZH}	Propagation delay time, high-impedance-to-high-level output	See Figure 4		5.4	15	ns
t_{PZL}	Propagation delay time, high-impedance-to-low-level output			2.5	15	ns
t_{PHZ}	Propagation delay time, high-level-to-high-impedance output			8.1	17	ns
t_{PLZ}	Propagation delay time, low-level-to-high-impedance output			7.3	15	ns

(1) All typical values are at T_A = 25°C and with V_{CC} = 3.3 V.
(2) $t_{sk(o)}$ is the maximum delay time difference between drivers on the same device.

PARAMETER MEASUREMENT INFORMATION

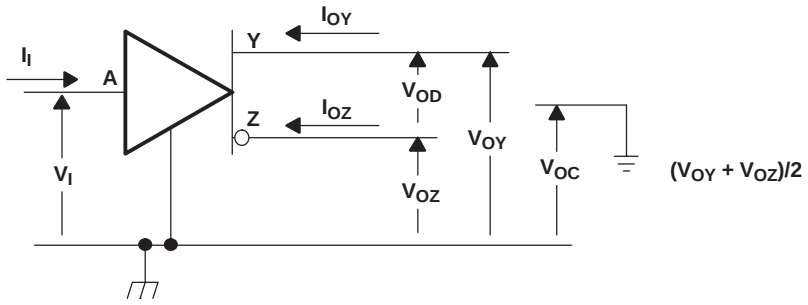
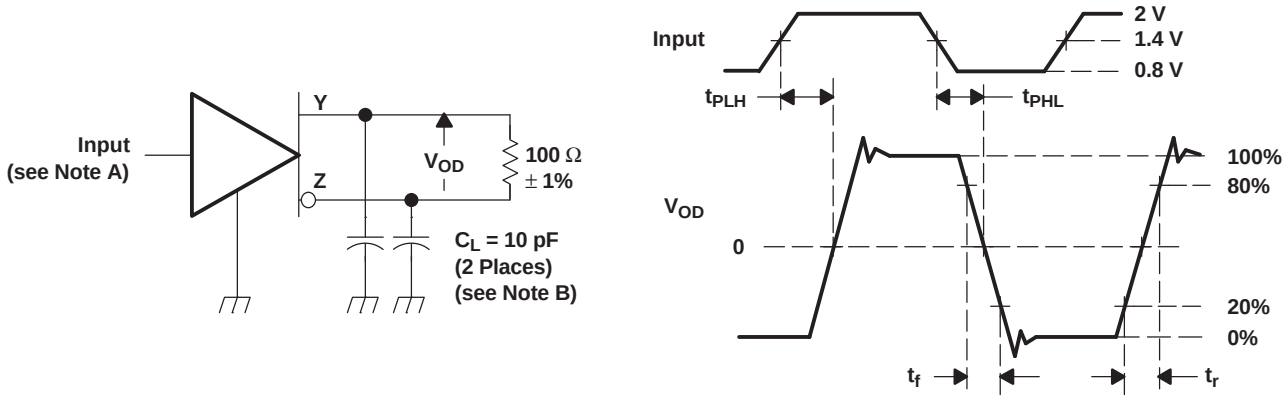


Figure 1. Voltage and Current Definitions

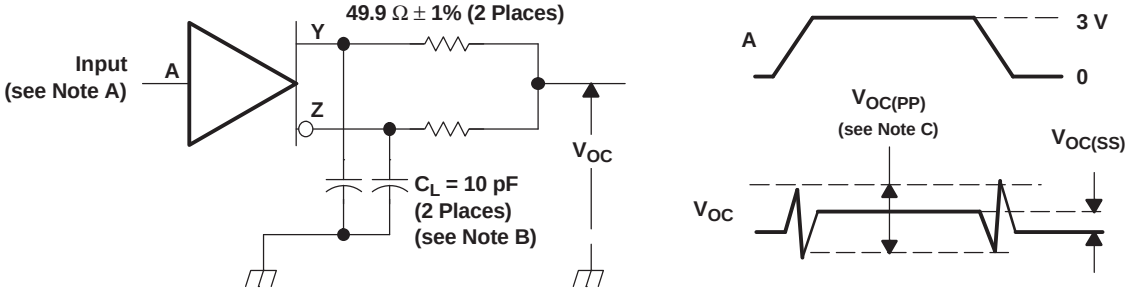


NOTES: A. All input pulses are supplied by a generator having the following characteristics: t_r or $t_f \leq$ 1 ns, pulse repetition rate (PRR) = 50 Mpps, pulse width = 10 ± 0.2 ns.
B. C_L includes instrumentation and fixture capacitance within 6 mm of the D.U.T.

Figure 2. Test Circuit, Timing, and Voltage Definitions for the Differential Output Signal

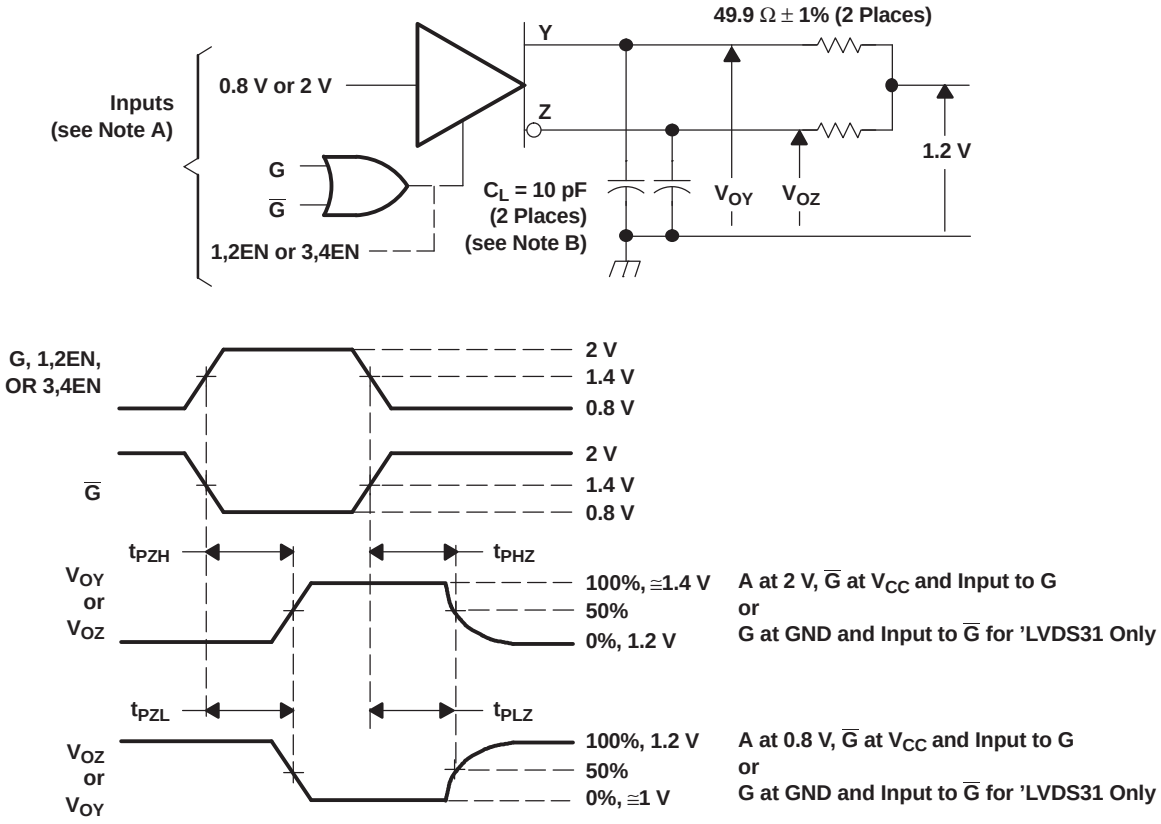
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PARAMETER MEASUREMENT INFORMATION (continued)



NOTES: A. All input pulses are supplied by a generator having the following characteristics: t_r or $t_f \leq 1$ ns, pulse repetition rate (PRR) = 50 Mpps, pulse width = 10 ± 0.2 ns.
B. C_L includes instrumentation and fixture capacitance within 6 mm of the D.U.T.
C. The measurement of $V_{OC(PP)}$ is made on test equipment with a –3-dB bandwidth of at least 300 MHz.

Figure 3. Test Circuit and Definitions for the Driver Common-Mode Output Voltage



NOTES: A. All input pulses are supplied by a generator having the following characteristics: t_r or t_f < 1 ns, pulse repetition rate (PRR) = 0.5 Mpps, pulse width = 500 ± 10 ns.
B. C_L includes instrumentation and fixture capacitance within 6 mm of the D.U.T.

Figure 4. Enable-/Disable-Time Circuit and Definitions

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TYPICAL CHARACTERISTICS

SUPPLY CURRENT vs FREQUENCY

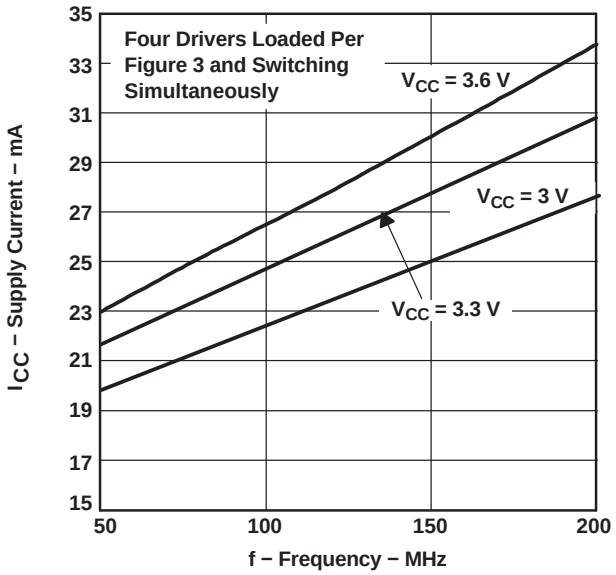


Figure 5.

LOW-TO-HIGH PROPAGATION DELAY TIME vs FREE-AIR TEMPERATURE

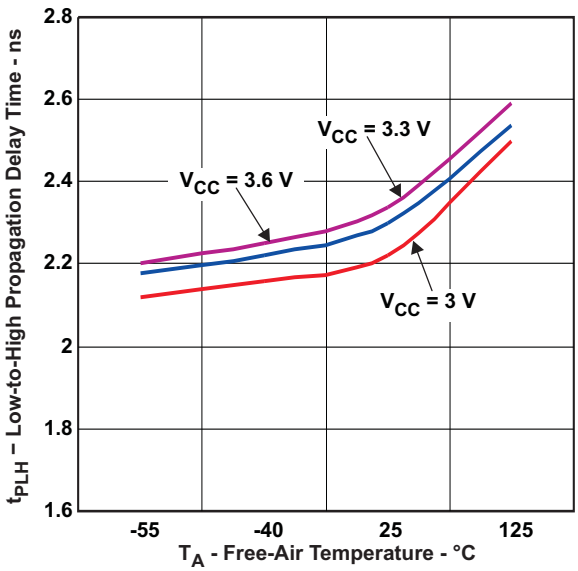


Figure 6.

HIGH-TO-LOW PROPAGATION DELAY TIME vs FREE-AIR TEMPERATURE

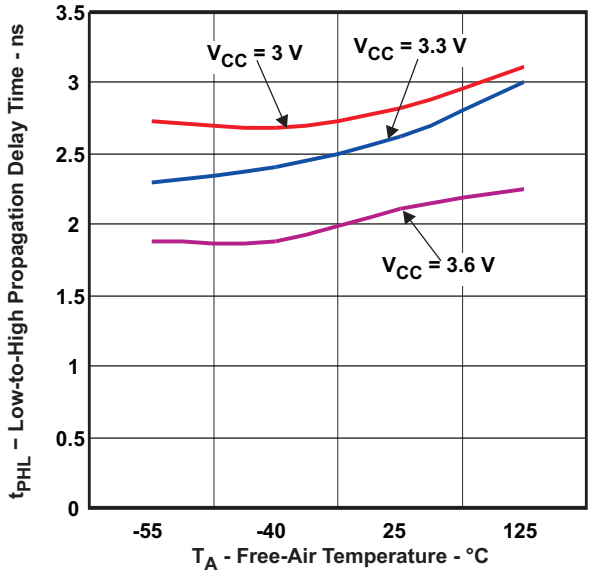
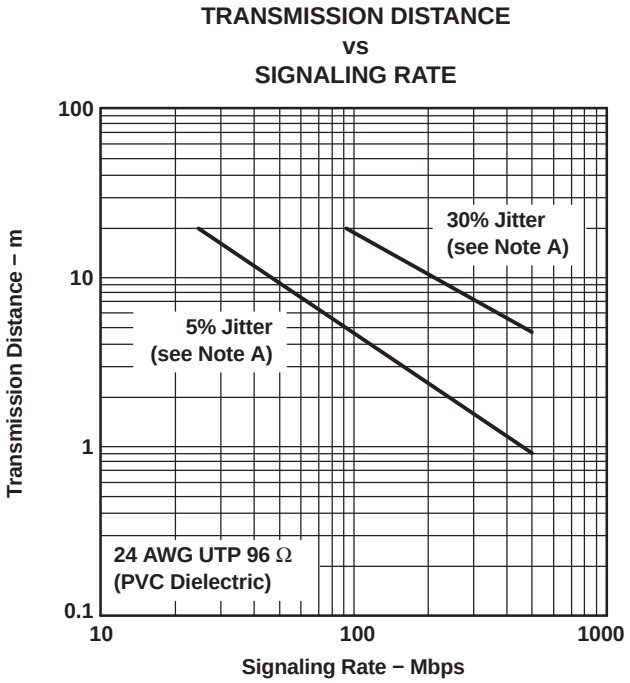


Figure 7.

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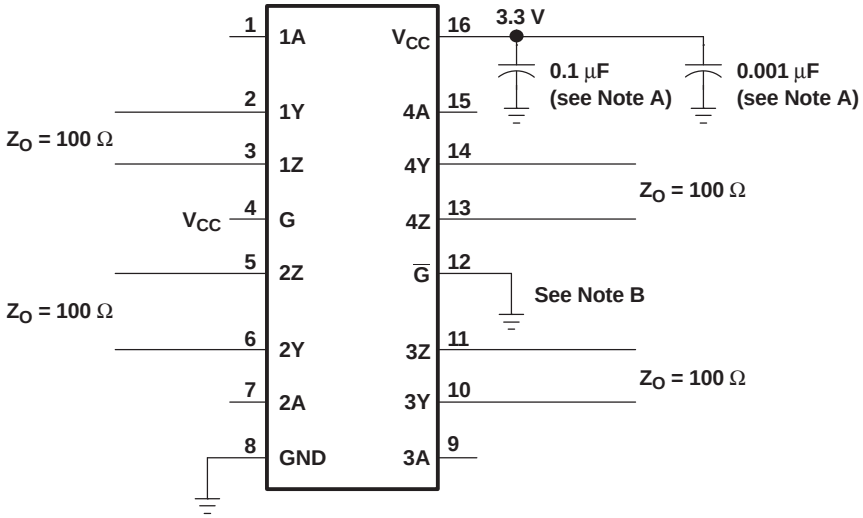
APPLICATION INFORMATION

The SN55LVDS31 is generally used as a building block for high-speed point-to-point data transmission where ground differences are less than 1 V. The SN55LVDS31 can interoperate with RS-422, PECL, and IEEE-P1596. Drivers/receivers approach ECL speeds without the power and dual supply requirements.



A. This parameter is the percentage of distortion of the unit interval (UI) with a pseudorandom data pattern.

Figure 8. Typical Transmission Distance Versus Signaling Rate

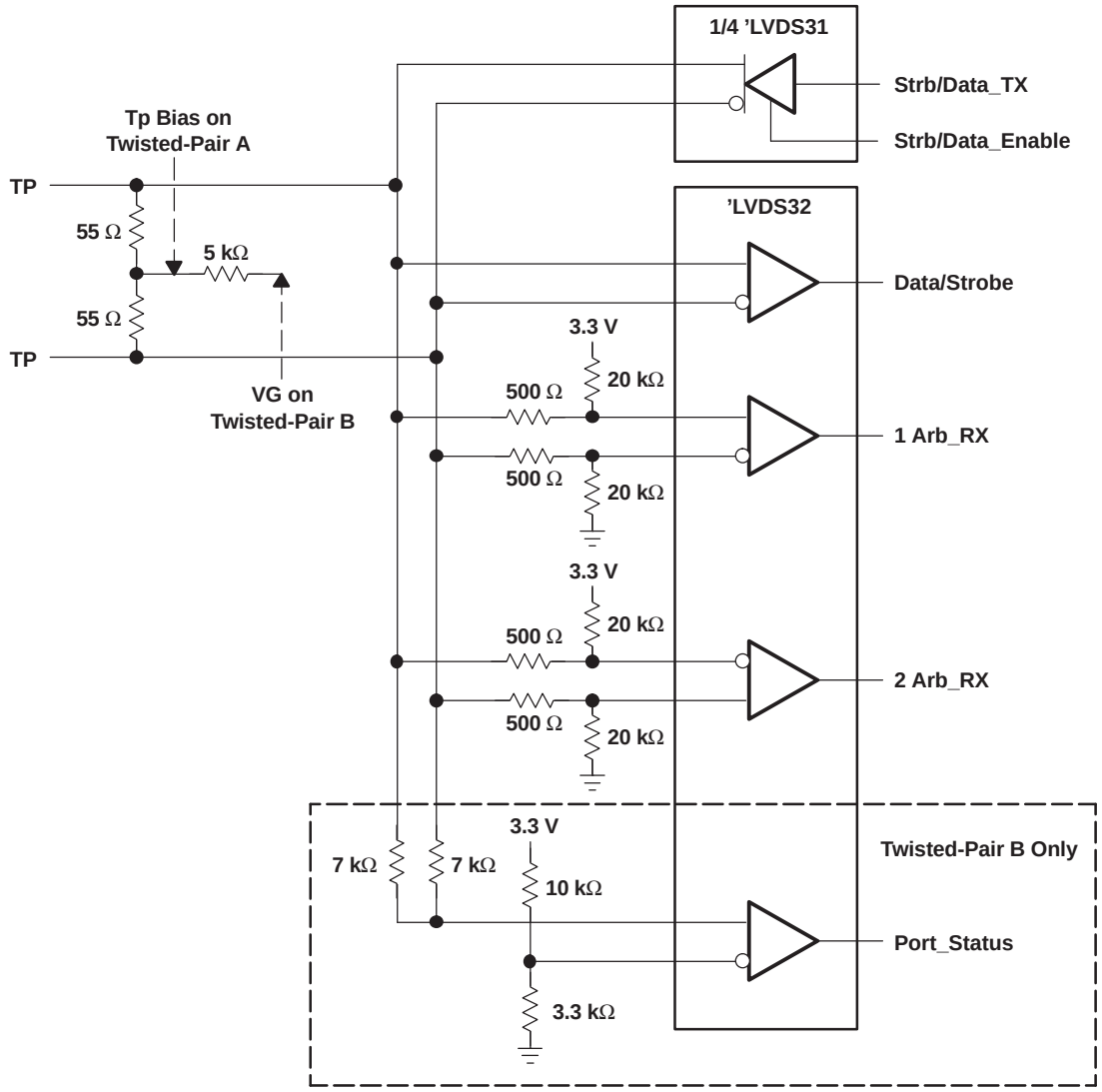


NOTES: A. Place a 0.1-μF and a 0.001-μF Z5U ceramic, mica, or polystyrene dielectric, 0805 size, chip capacitor between V_{CC} and the ground plane. The capacitors should be located as close as possible to the device terminals.

B. Unused enable inputs should be tied to V_{CC} or GND, as appropriate.

Figure 9. Typical Application Circuit Schematic

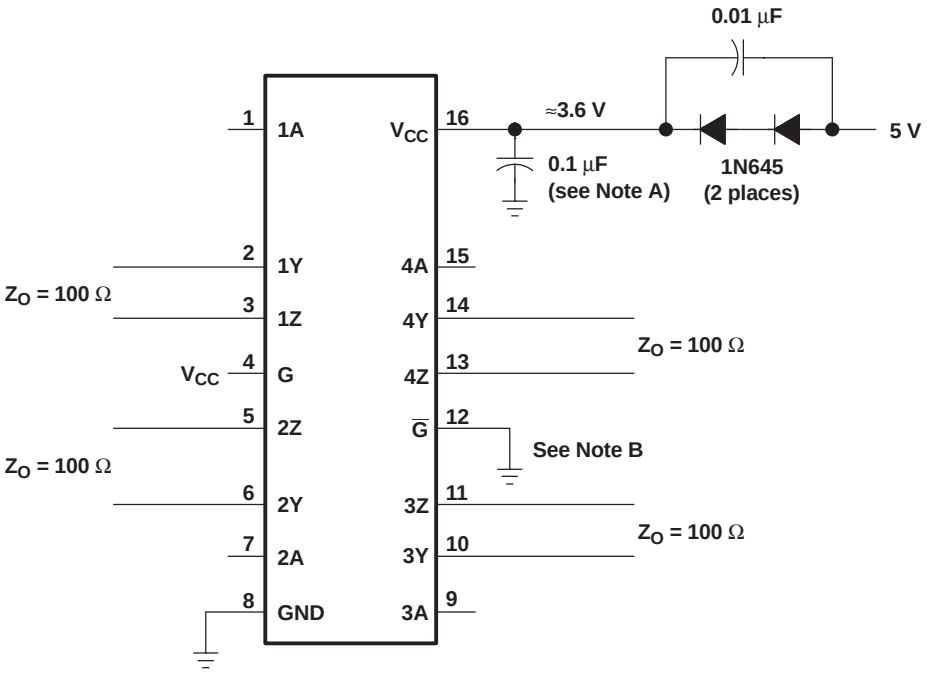
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NOTES: A. Resistors are leadless, thick film (0603), 5% tolerance.
B. Decoupling capacitance is not shown, but recommended.
C. V_{CC} is 3 V to 3.6 V.
D. The differential output voltage of the 'LVDS31 can exceed that specified by IEEE1394.

Figure 10. 100-Mbps IEEE 1394 Transceiver

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A. Place a 0.1-µF Z5U ceramic, mica, or polystyrene dielectric, 0805 size, chip capacitor between V_{CC} and the ground plane. The capacitor should be located as close as possible to the device terminals.

B. Unused enable inputs should be tied to V_{CC} or GND, as appropriate.

Figure 11. Operation With 5-V Supply

COLD SPARING

Systems using cold sparing have a redundant device electrically connected without power supplied. To support this configuration, the spare must present a high-input impedance to the system so that it does not draw appreciable power. In cold sparing, voltage may be applied to an I/O before and during power up of a device. When the device is powered off, V_{CC} must be clamped to ground and the I/O voltages applied must be within the specified recommended operating conditions.

RELATED INFORMATION

IBIS modeling is available for this device. Contact the local TI sales office or the TI Web site at www.ti.com for more information.

For more application guidelines, see the following documents:

- *Low-Voltage Differential Signaling Design Notes* (SLLA014)
- *Interface Circuits for TIA/EIA-644* (LVDS) (SLLA038)
- *Reducing EMI With LVDS* (SLLA030)
- *Slew Rate Control of LVDS Circuits* (SLLA034)
- *Using an LVDS Receiver With RS-422 Data* (SLLA031)

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PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package | Pins	Package qty | Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
5962-9762101VFA	Active	Production	CFP (W) | 16	25 | TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	5962-9762101VF A SNV55LVDS31W

(1) **Status:** For more details on status, see our product life cycle.

(2) **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

(3) **RoHS values:** Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

(4) **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

(5) **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

(6) **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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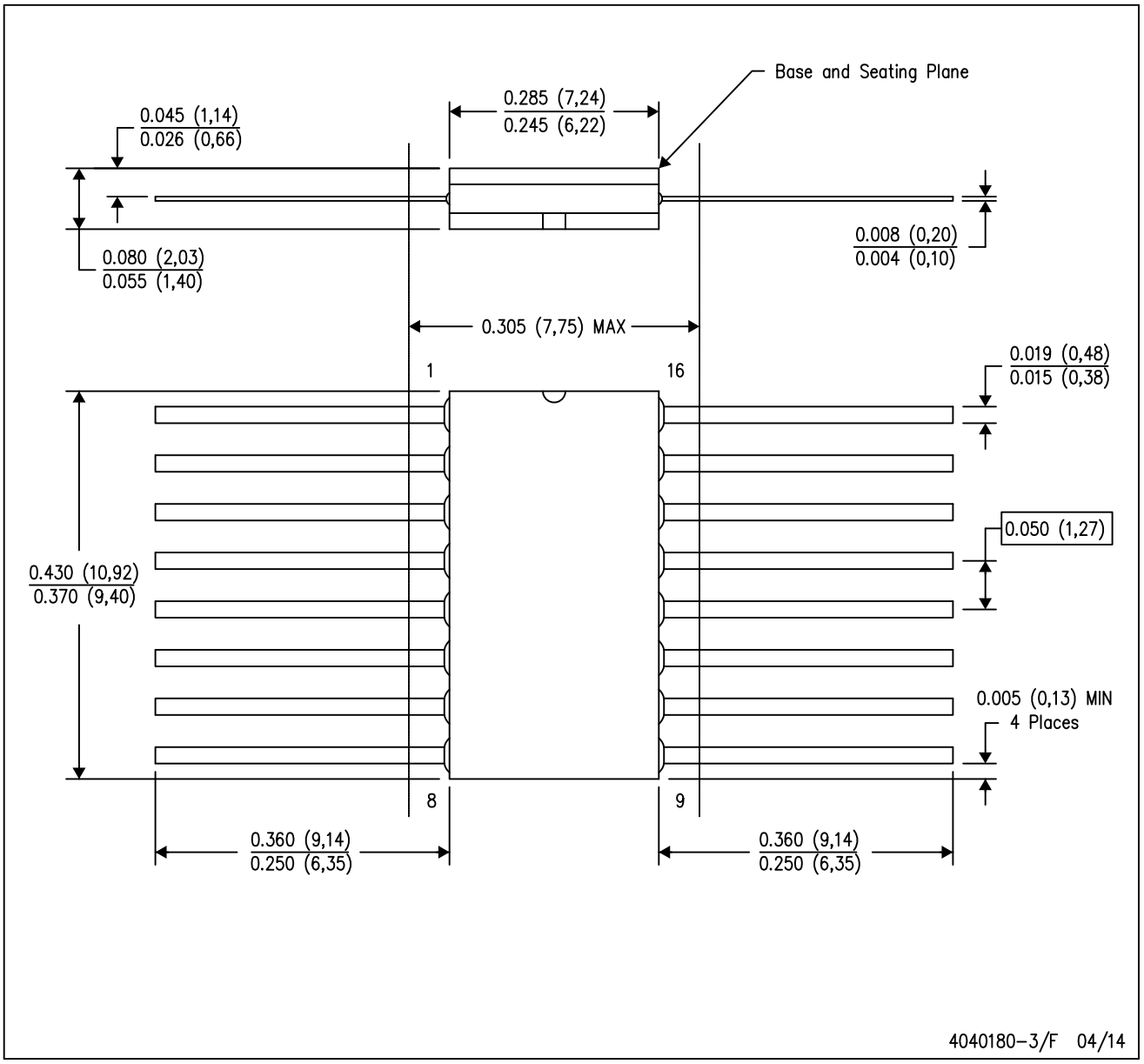
OTHER QUALIFIED VERSIONS OF SN55LVDS31-SP :

- Catalog : SN55LVDS31

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product

W (R–GDFP–F16) CERAMIC DUAL FLATPACK



NOTES:
A. All linear dimensions are in inches (millimeters).
B. This drawing is subject to change without notice.
C. This package can be hermetically sealed with a ceramic lid using glass frit.
D. Index point is provided on cap for terminal identification only.
E. Falls within MIL STD 1835 GDFP2–F16

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最后更新日期：2025 年 10 月